

Notice of References Cited	Application/Control No. 10/763,174	Applicant(s)/Patent Under Reexamination TANZAWA ET AL.	
	Examiner Hiep Nguyen	Art Unit 2816	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,163,190	12-2000	Takai et al.	327/205
	B	US-			
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	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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